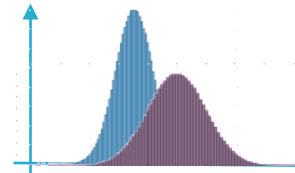
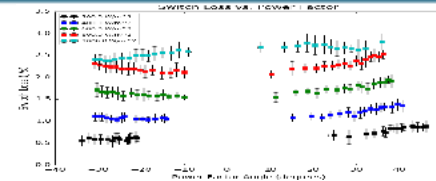
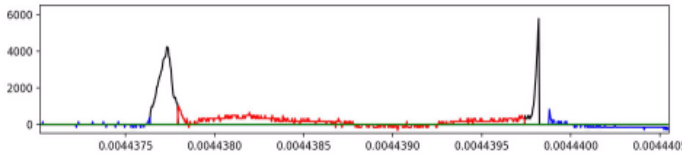
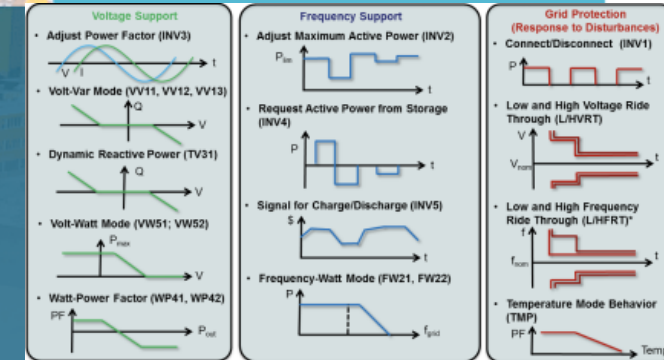




PV inverter reliability: Advanced Inverter Functionality



Jack D. Flicker

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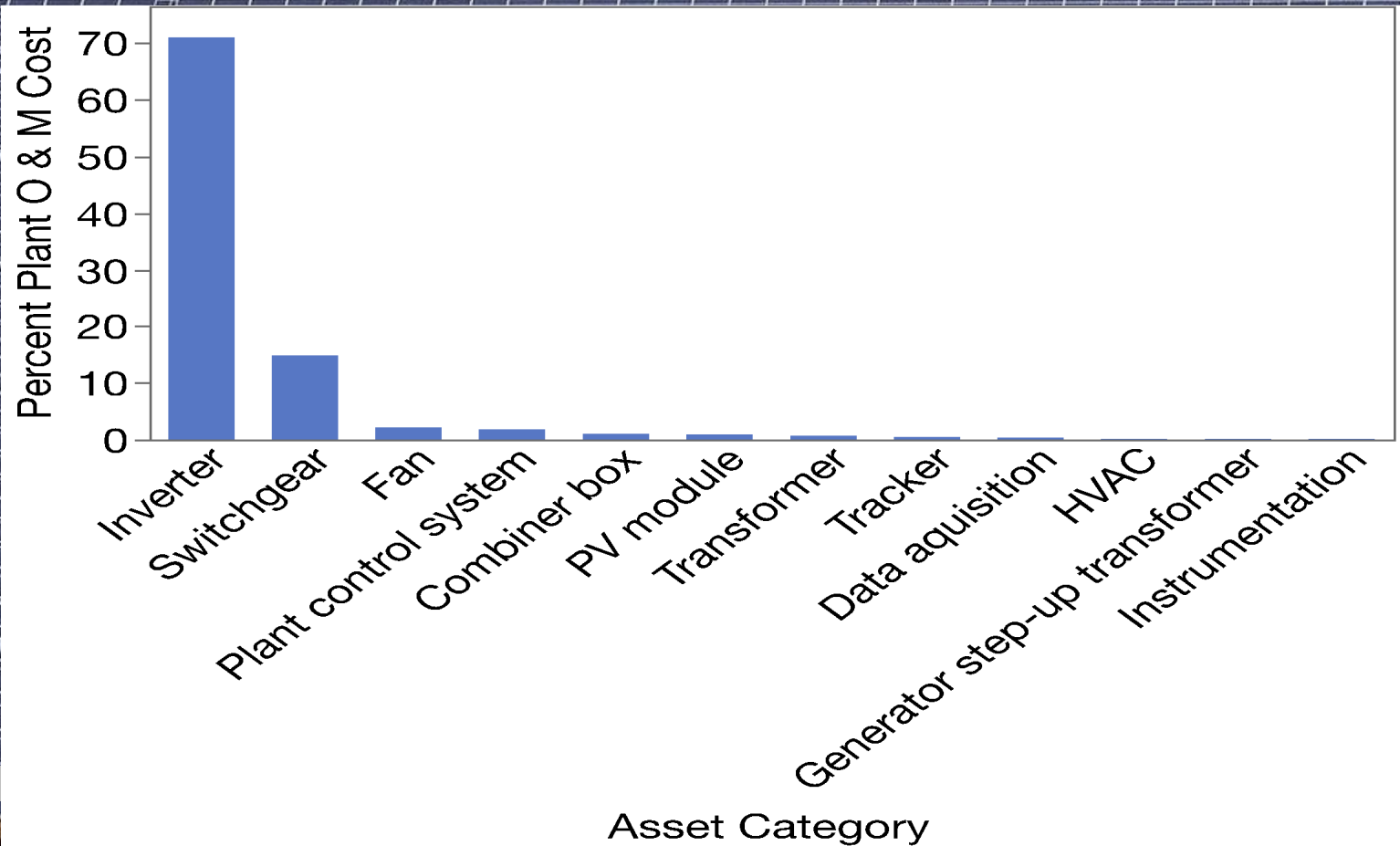
IEEE Energy Conversion Congress and Exposition (ECCE)

October 12, 2022



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Who does the heavy lifting in a PV system?



- Inverters are complicated machines
 - Power Conditioning
 - Grid Monitoring
 - Array reporting/monitoring
 - Islanding protection, etc.
- Handling much higher power densities than rest of the system
- Must endure harsh environments with large temperature cycles (ambient and power handling)
 - Increased DC/AC ratios
 - Operating at P_{rated} most of day
- Not only is reliability more challenging, but more consequential when failures occur

...and operational capabilities will only increase over time

Advanced Inverter Operations and Reliability (1/2)



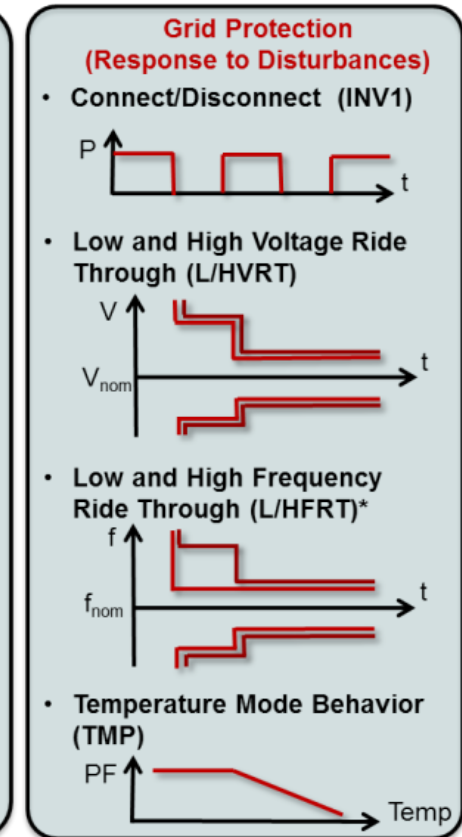
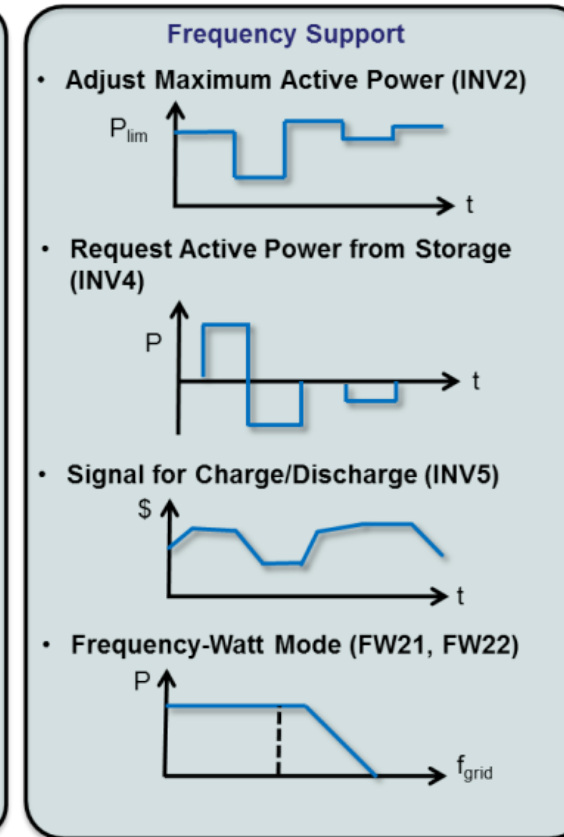
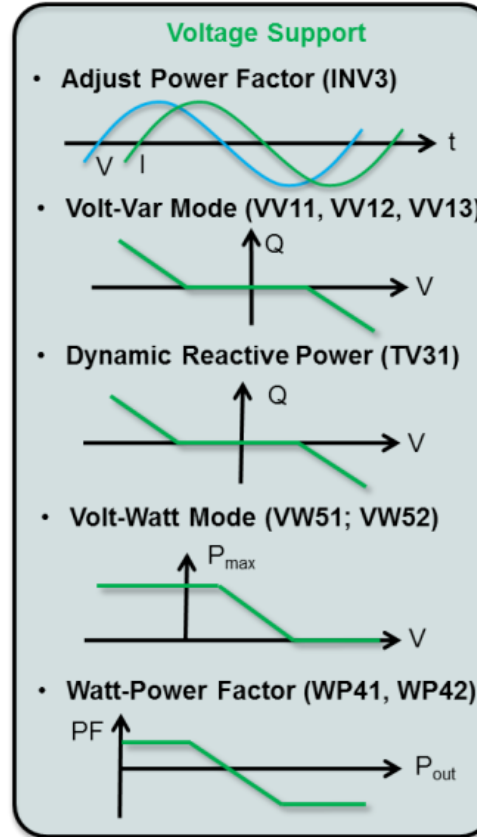
3

- Historically, inverters have had a very simple objective:

- Convert DC power to AC power regardless of grid conditions.
- Maximize power injected into the grid.

- Monumental shifts in inverter operations occurred Sept 8th 2017:

- HI and CA required advanced inverter functionalities.
- Inverters expected to not only inject power, but also support the grid through advanced inverter functions.
 - *Voltage support, frequency support, or grid disturbance.*
- IEEE 1547-2018 standardized for all of U.S.
- Inverters become “good grid-izens”



Advanced functions as defined in IEC TR 61850-90-7.

*FRT not included in IEC 61850-90-7, but is in Sandia Test Protocols.

Advanced Inverter Operations and Reliability (2/2)

4

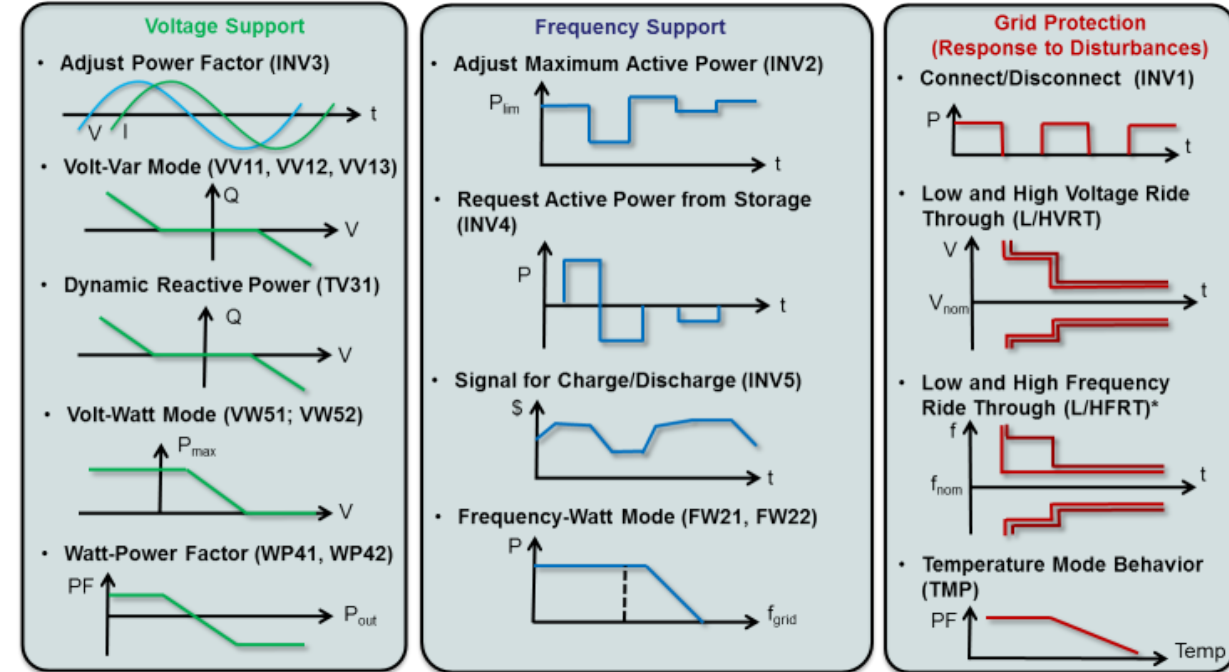


- Many units no longer operate at “nominal” usage conditions.
- Impact of advanced inverter functions on lost revenue (e.g. curtailment) have been considered.
- Little to no discussion in long-term reliability impact of advanced inverter functions.

Will an inverter operating at non-nominal operating conditions have a significant effect on inverter reliability?

Does this require updated reliability testing protocols (by either manufacturers or standards making bodies) to capture this?

- Using the System Validation Platform (SVP):
 - We have instrumented and autonomously measured inverter component stress for a variety of different advanced inverter operating conditions
 - Originally developed as flexible framework to autonomously measure system-level inverter operations for certification



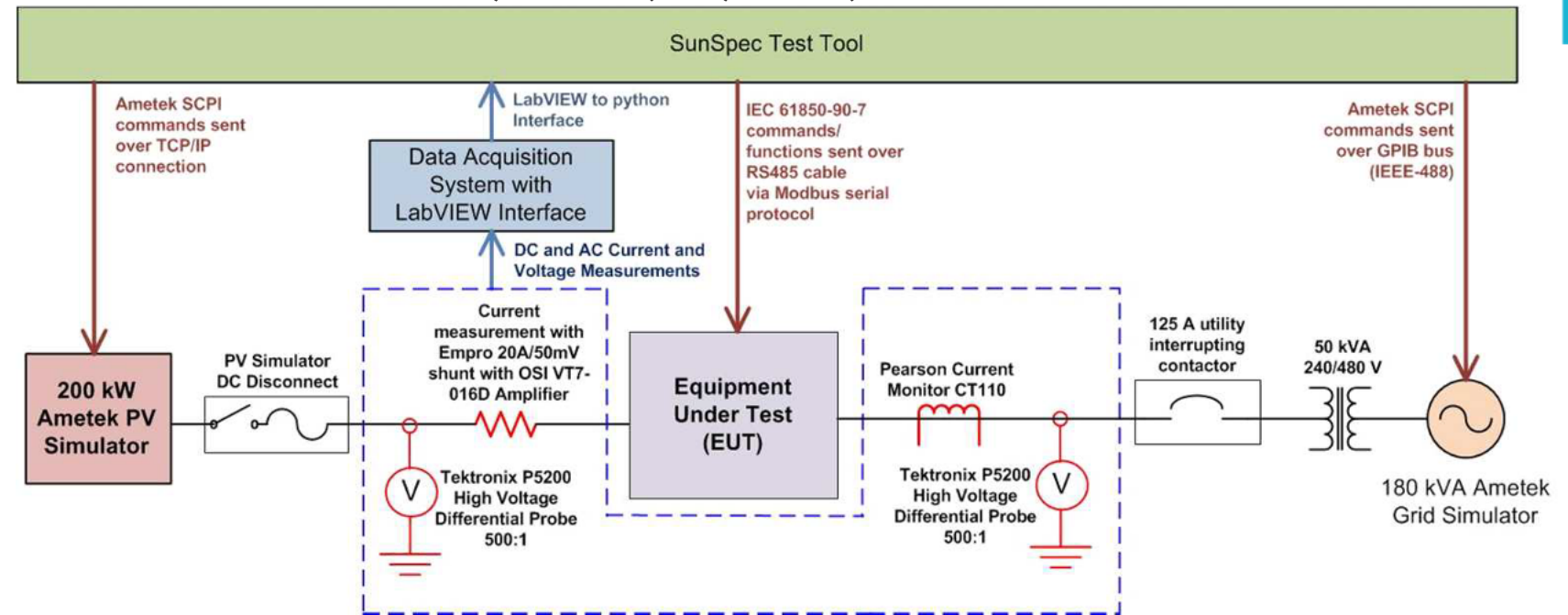
Advanced functions as defined in IEC TR 61850-90-7.

*FRT not included in IEC 61850-90-7, but is in Sandia Test Protocols.

System Validation Platform (SVP) (1/2)

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- The open-source System Validation Platform (SVP) initially developed under a Cooperative Research and Development Agreement (CRADA) between Sandia National Laboratories and SunSpec Alliance.



- Range of equipment drivers and test scripts for DER interoperability/electrical characterization experiments.
- Software platform written in Python:
 - Includes ability to script actions for multiple hardware devices .
 - Uses a library of device drivers and abstraction layers:
 - Drivers have been created for PV simulators, grid simulators, DER, data acquisition systems, load banks, and switches
 - Allows the same test logic (SVP scripts) to be run at multiple laboratories with different equipment.
 - Originally developed for interoperability requirements: IEEE 1547.1, UL1741 SA, and IEC TR 61850-90-7

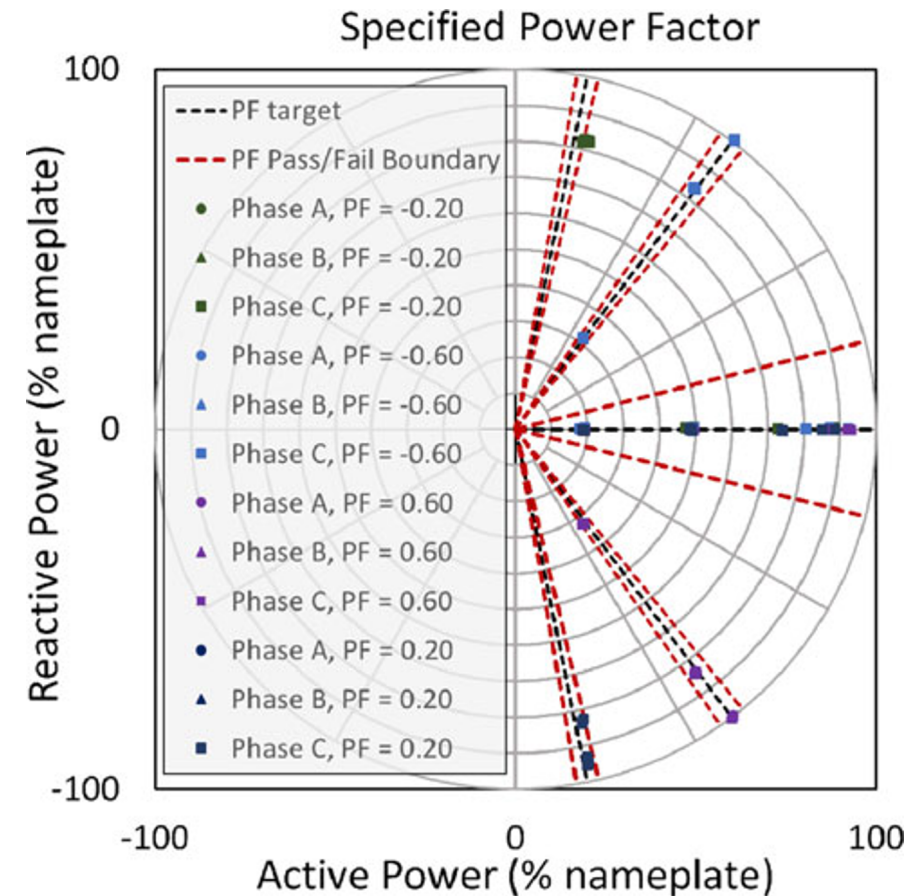
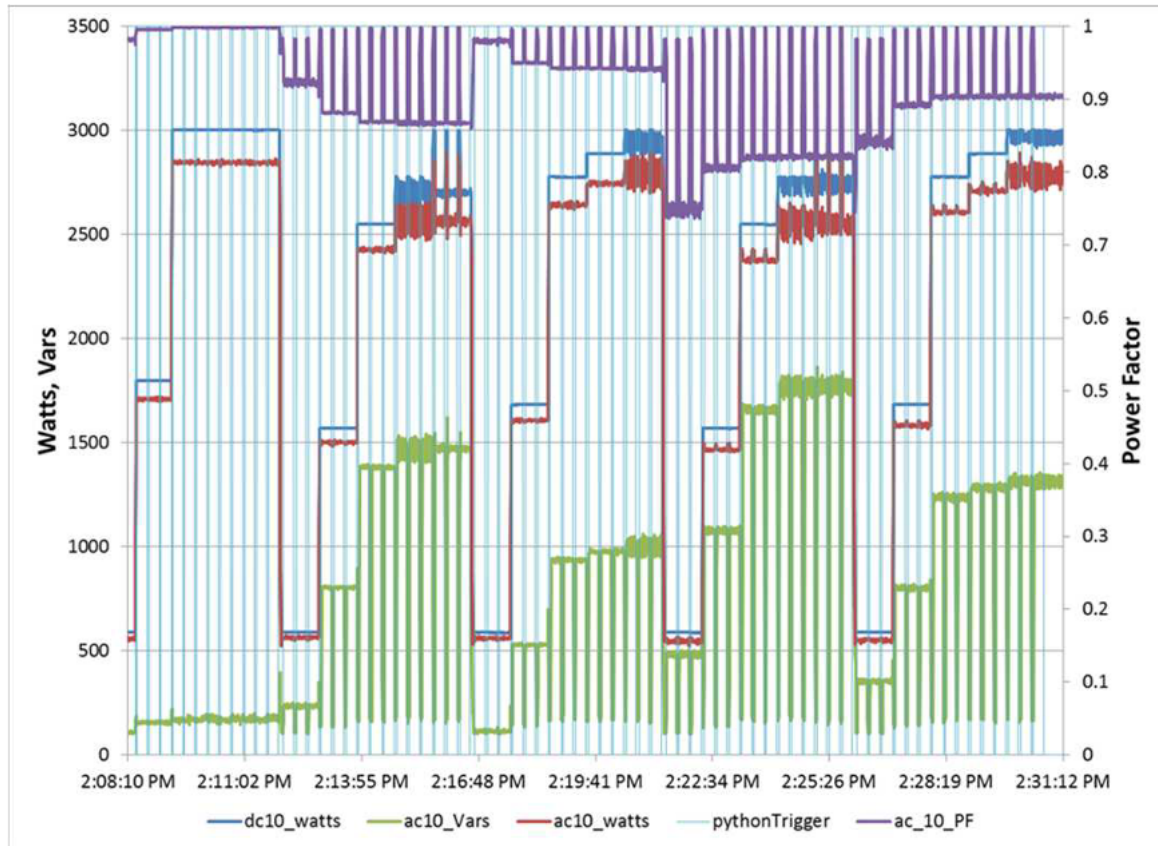
Used to autonomously evaluate parameterized operation conditions over entire operation range

System Validation Platform (SVP) (2/2)



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- UL 1741 SA test permutations are large due to the number of settings in each advanced DER function:
 - ~75 measurements for fixed power factor → *25 minutes with SVP*
 - ~375 measurements for volt/var - → *90 minutes with SVP*



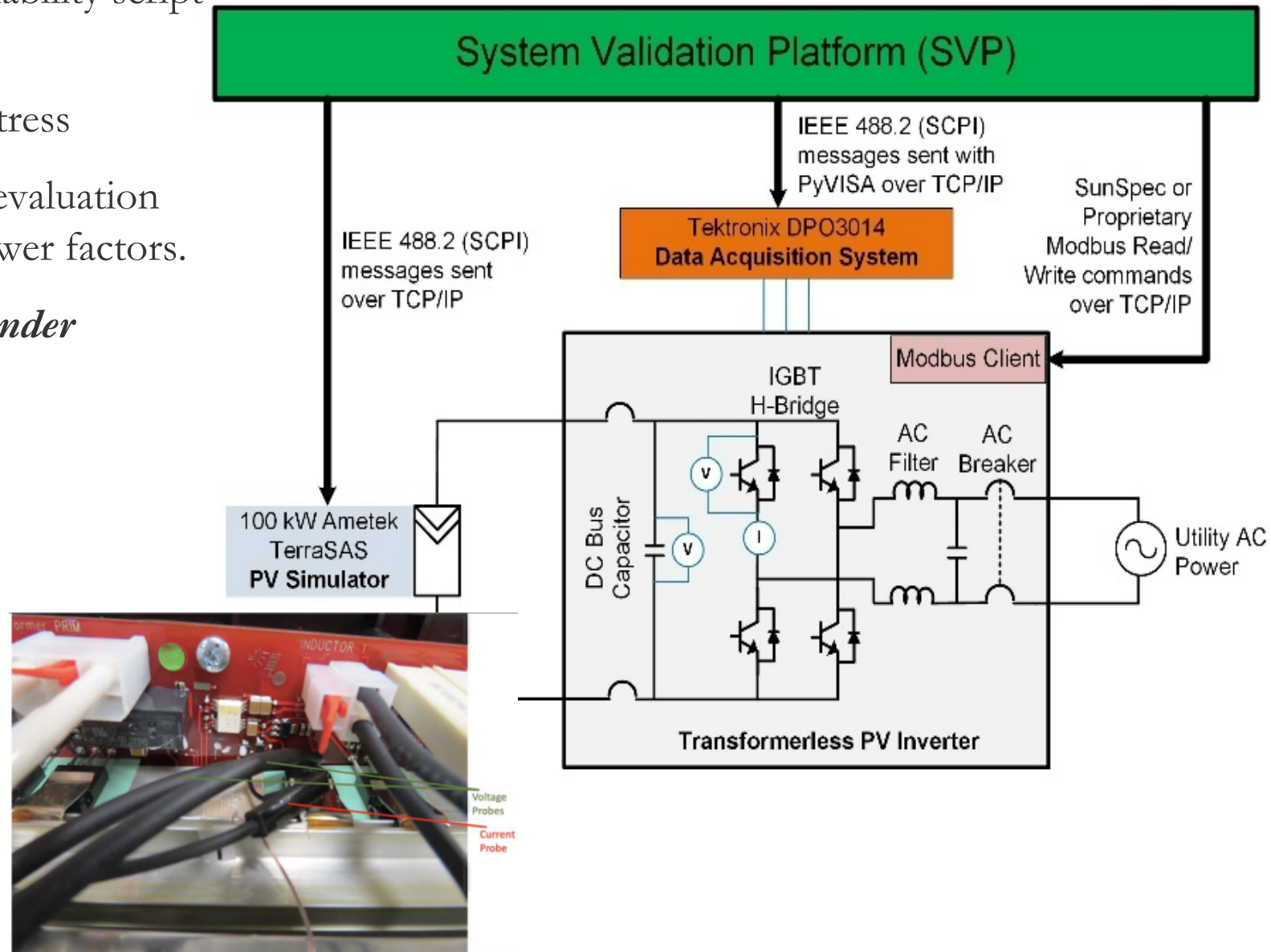
Instead of characterizing the ability of the system to perform advanced inverter functions, can we harness SVP to calculate component level stress metrics over a range of advanced inverter functions?

Harnessing SVP for Reliability Measurements



7

- New Tektronix oscilloscope driver and reliability script were created
- Directly measures/calculates component stress
- Paired with SVP script to automate stress evaluation for a range of PV irradiance values and power factors.
- *Produce inverter component stress maps under different operating conditions*
- Allows for flexible measurement of any accessible component inside the inverter
 - switches, capacitors, inductors, etc.
- Set of experiments to measure loss of **switches in H-bridge** and **DC bus capacitor**



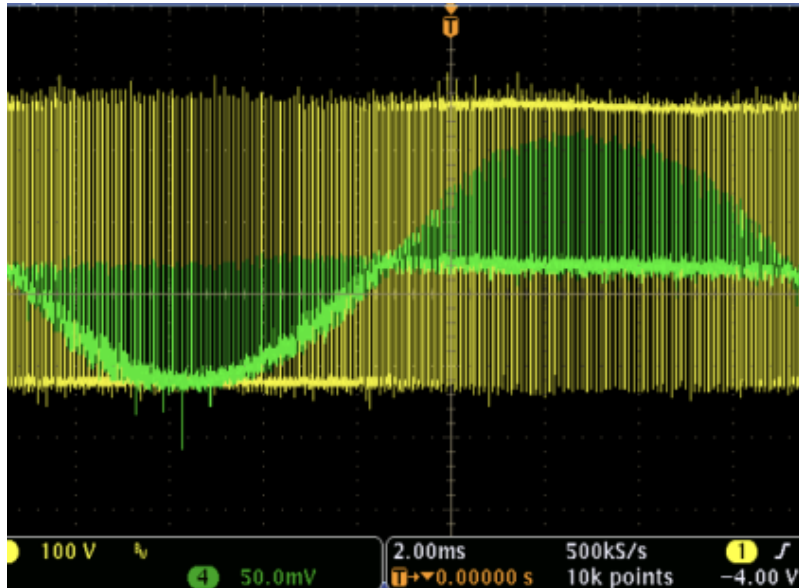
Measuring loss in H-bridge Switch –Setup

8.

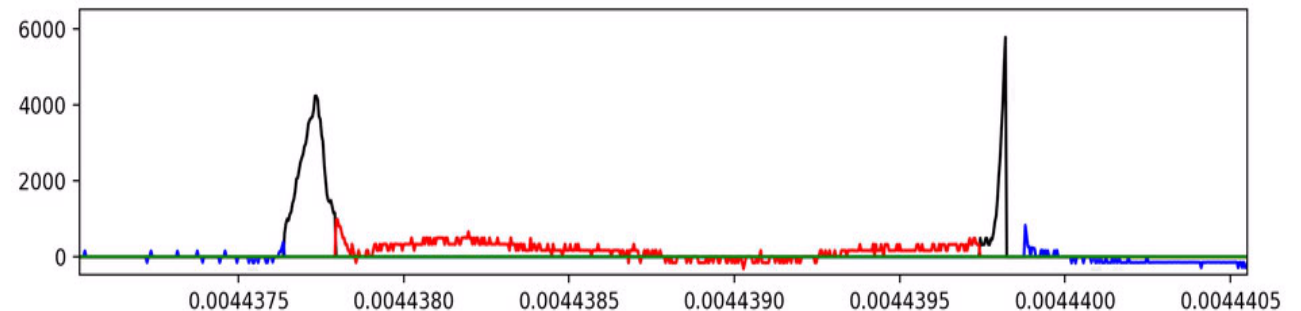
- Autonomous run carried out to measure MOSFET switch loss in H-bridge:
 - Single-phase, 3 kW inverter.
 - Loss measured at power factors from -0.85 to 0.85 in 0.01 increments.
 - At each PF, 20 measurements taken serially and averaged together
 - Irradiance values of 200 W/m² to 1000 W/m² in 200 W/m² increments.

4. Increment PF, irradiance, etc.

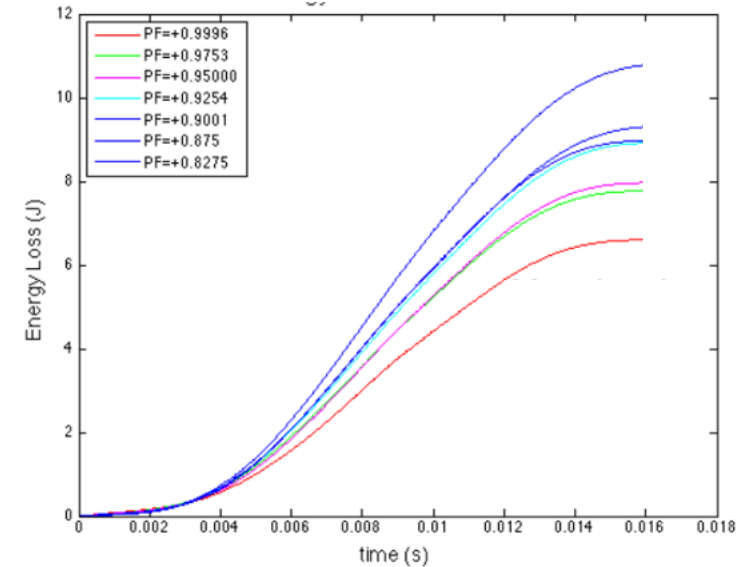
1. Measure Switch Voltage/Current



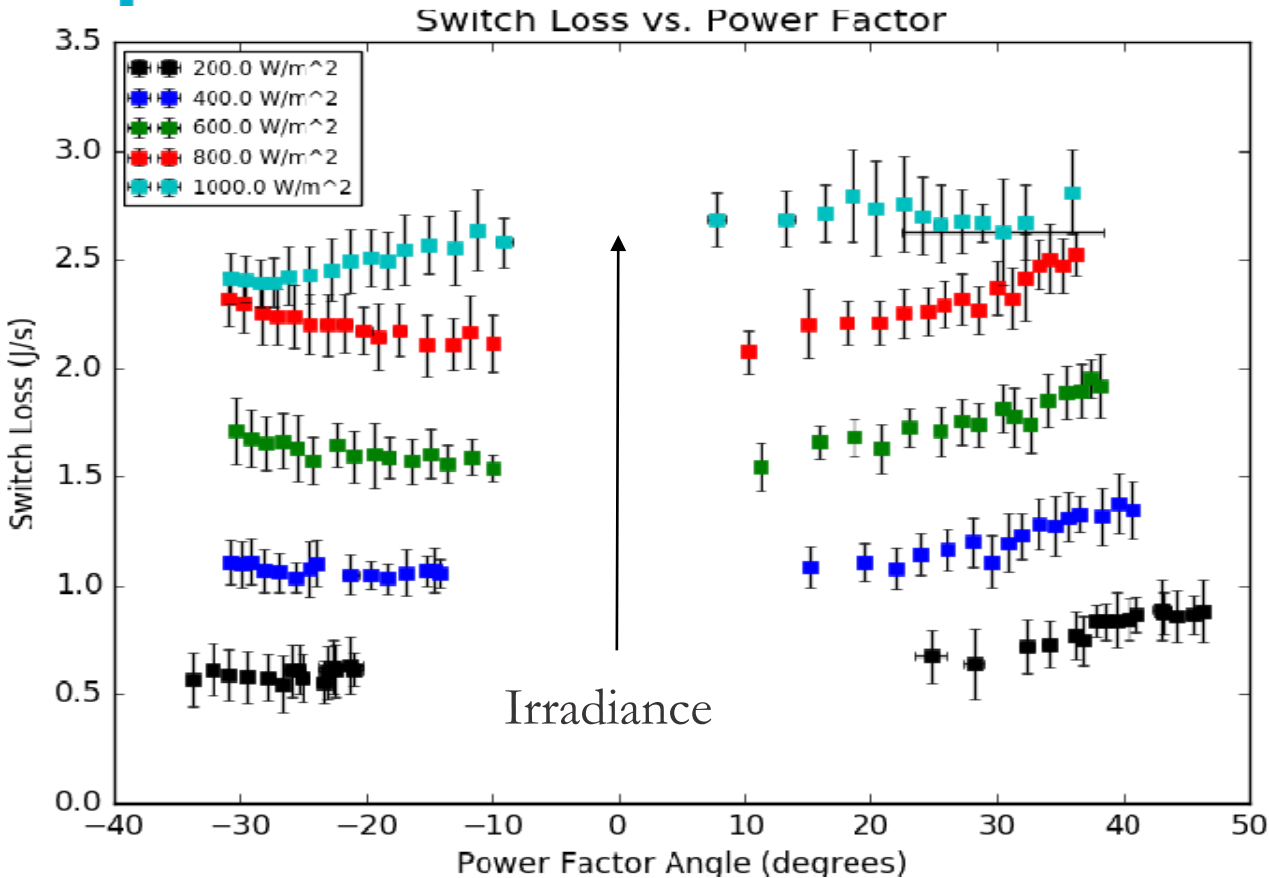
2. Calculate Switch Power



3. Cumulative switch loss per cycle



Measuring loss in H-bridge Switch –Results



- System level efficiency shows increased loss:
 - With increased irradiance.
 - At increased positive power factor.
- Total change in efficiency is approximately 1%:
 - Additional ~30 W of loss at high PF.
- Switching loss is directly related to:
 - Irradiance level.
 - Positive power factor:
 - At high irradiance, also increase in switch loss for negative power factor.
 - Minimum loss at unity PF.

- 1000 W/m² measurement switching loss affected by system curtailment.
- Corresponds to device loss map as a function of irradiance and PF.

How can we use loss maps to extract information about expected useful life?

Preliminary Lifetime Calculations (1/4)

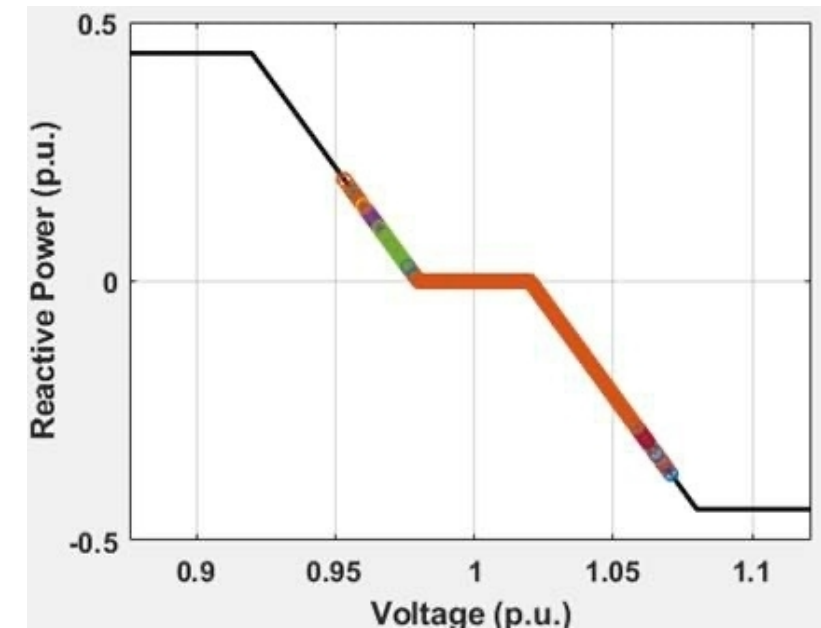
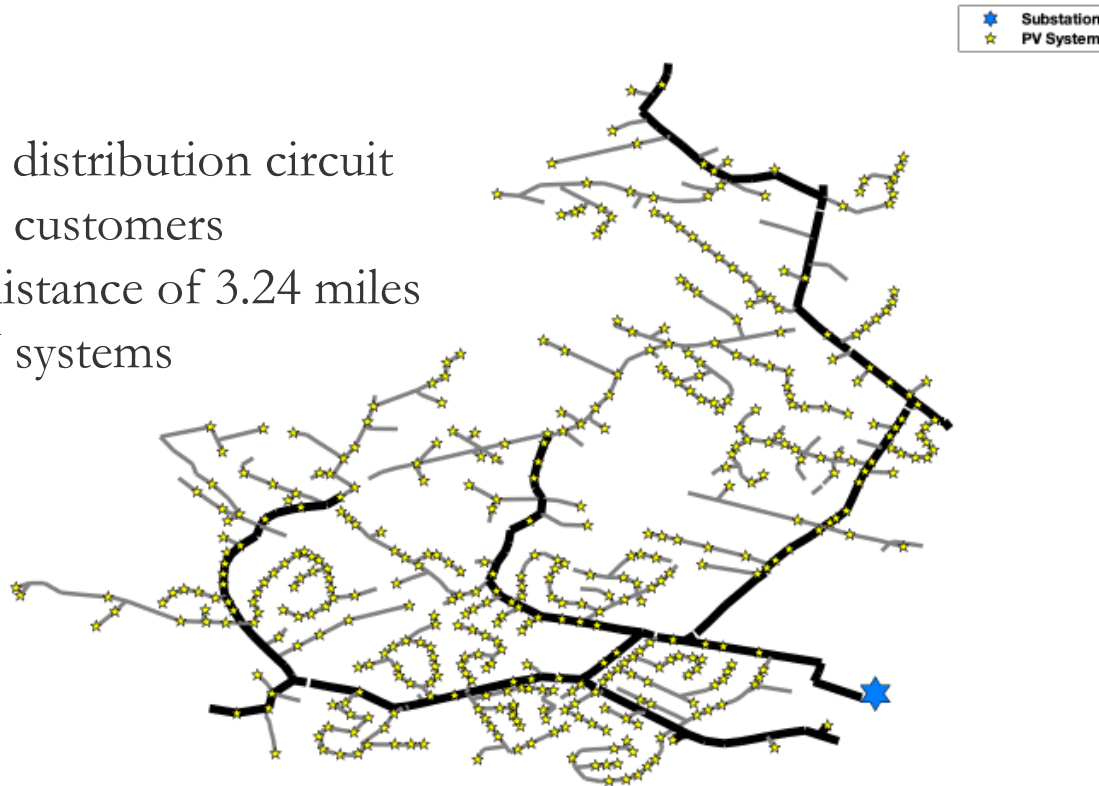


10

- In any real system inverters respond based on programmed Volt-VAr curves
- Utilized quasi-static time series (QSTS) simulations modified EPRI Ckt5 test feeder
 - Yields time series power data (real/reactive) for each inverter in system
 - Based on pre-programmed advanced inverter operation profile

Ckt5 Feeder

- Actual 12.47 kV distribution circuit
- 1,379 residential customers
- Maximum bus distance of 3.24 miles
- Total of 701 PV systems



Operating points of all 701 inverters at a single time step for IEEE 1547 Category B

- J. A. Azzolini and M. J. Reno, "Impact of Load Allocation and High Penetration PV Modeling on QSTS-Based Curtailment Studies," in *IEEE Power & Energy Society General Meeting (PESGM)*, 2021.
- EPRI, "Enhanced Load Modeling: Leveraging Expanded Monitoring and Metering," vol. 3002015283, 2019.

Preliminary Lifetime Calculations (2/4)

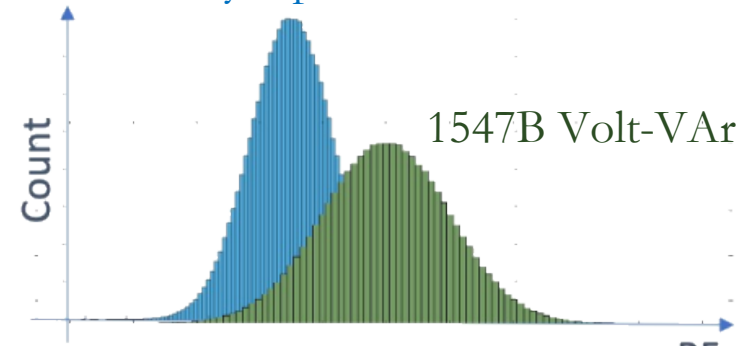
Operational System

Advanced Inverter Mission Profile

Unity Operation

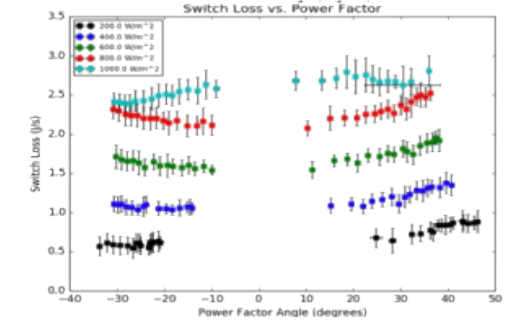
★ Substation
★ PV System

QSTS
Results



PF

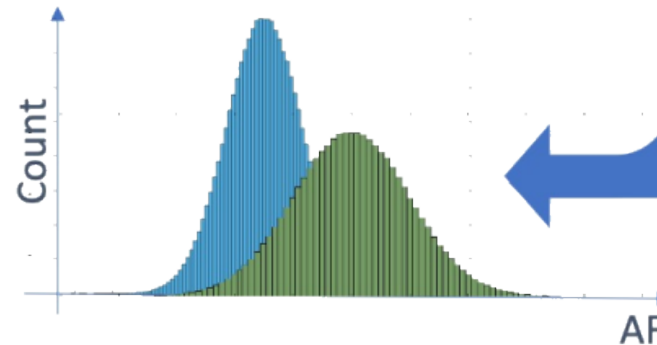
Component Stress Map



Lifetime Model

$$A_F = e^{\frac{E_a}{R} \left(\frac{1}{T_j^{InVA}} - \frac{1}{T_j^{InVB}} \right)}$$

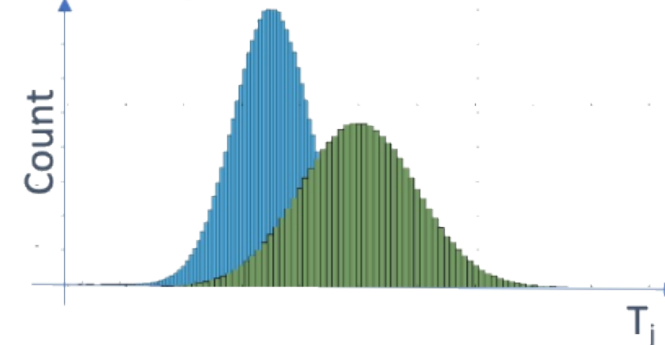
AF Collective



Average Relative Aging Factor

$$\frac{1}{A_{F,avg}} = \sum_i \frac{p_i}{A_{F,i}}$$

Component Stress Profile

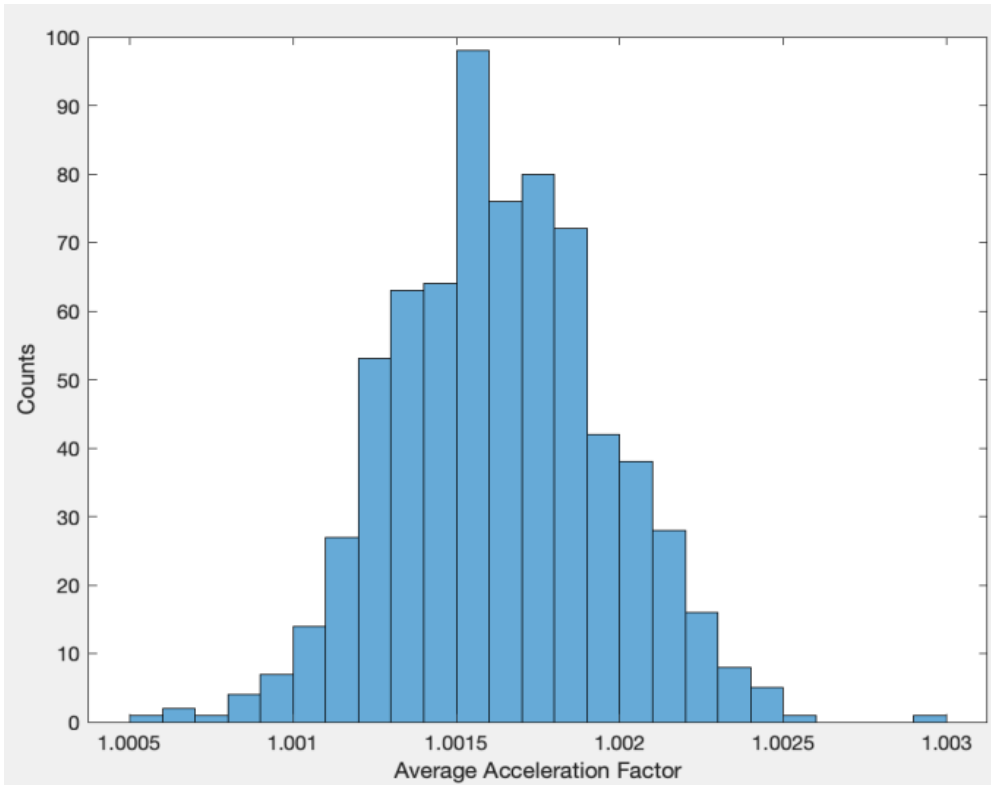


NB: Same process for any pairwise comparison. Same inverter with different operating modes or two different inverters in system
This is a general framework, can substitute in any system, operating mode, stress map, and lifetime model

Preliminary Lifetime Calculations (3/4)



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- Mean AF_{avg} for inverters in the system :
 - 1.0015 ± 0.00033
- Incorporation of IEEE 1547 Category B volt-var curve results in only a **0.15% faster degradation** rate for the median inverter
- If standard inverter has a 20-year lifetime, the median inverter would fail only **12 days earlier**
- Depending on assumptions → corner case up to **1.8% faster degradation**
 - 4.5 month earlier failure

Problem solved!?

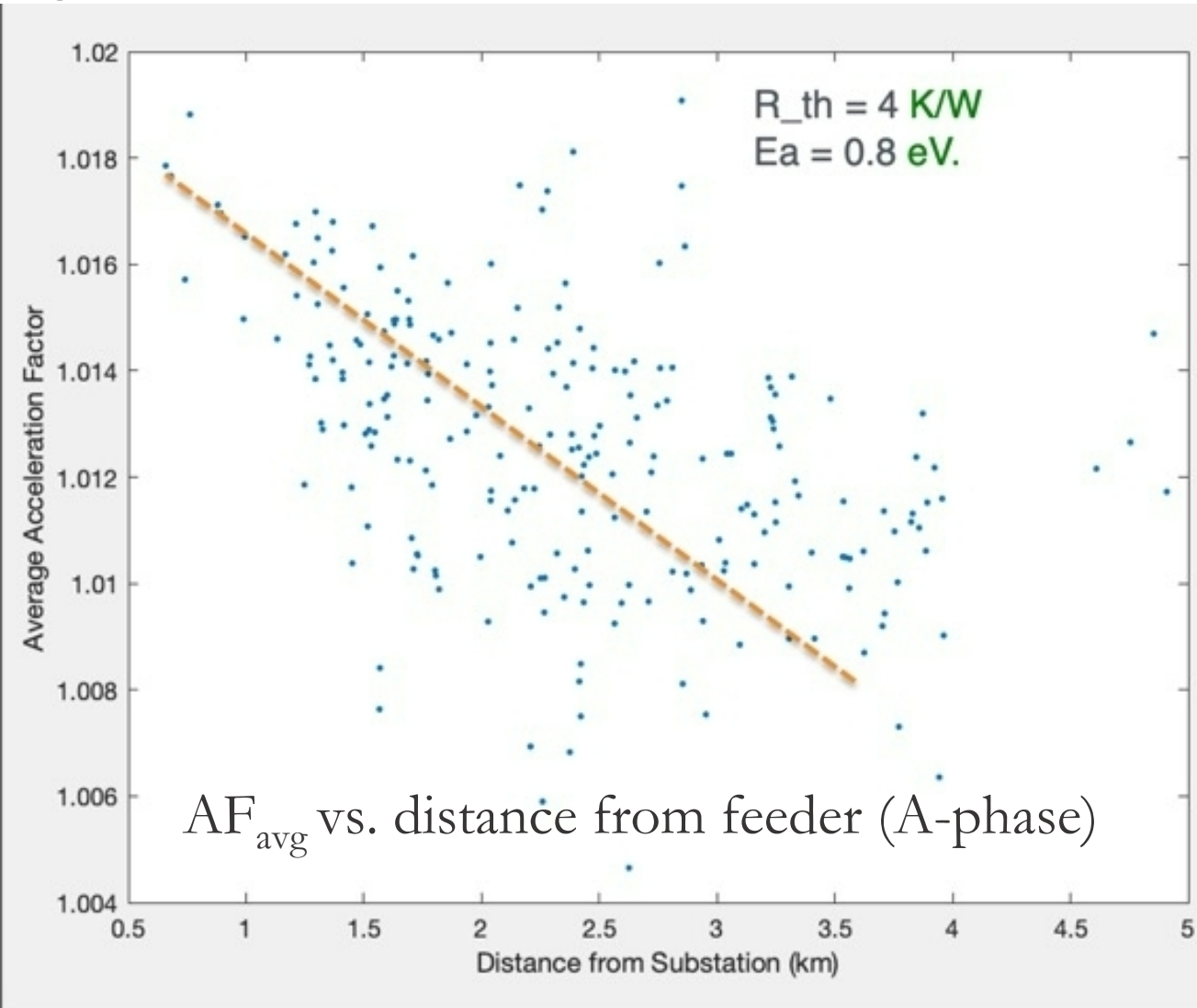
Probably not

- Calculated relative change in average acceleration factor (AF_{avg}) for 701 inverters operating in EPRI Ckt5 test feeder
- Compared static unity power factor (PF=1) vs. IEEE 1547 Category B default volt-var curve
- Indicates that switching loss is **probably not** limiting failure mechanism for Volt-Var operation
- Need to evaluate for **all other** competing failure mechanisms
 - 100s to 1000s of other mechanisms

Preliminary Lifetime Calculations (4/4)



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- Extract information on individual inverters in system
- Aging rate for inverters correlated to **distance from the substation**
 - Additional aging -0.25%/km from substation
 - Inverters closer to substation experience *greater stress*
- Substation operates at high end of ANSI (~ 1.05 pu) to offset low voltage at end of feeder
- Inverters near substation work more often to lower the voltage *and* against stiff substation interconnect
 - Operate at non-unity more often *and* at higher PF than the inverters at ends of feeder

NB: Results *highly* dependent on system specifics (line length, voltage, inverter number/placement, etc.).

Not necessarily generalizable to all systems



- Inverters are required to be good “grid-izens” and provide grid support through *advanced inverter operating functions*
- These functions may introduce additional stress compared to typical operational conditions
- Significant evaluation and testing is required to understand impacts to inverter reliability, similar to certification testing (but harder)
- Introduced *general experimental and simulation framework* to couple experimental component-level stress measurement data with system-level operational data
 - SVP used to autonomously evaluate component stress for parameterized operating conditions
 - QSTS simulations used to model expected inverter power factor operation 701 inverters
 - Degradation due to switch loss from volt-var operation *is not* a significant contributor to early failure

Thank you



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Principle Member of Technical Staff

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